

- gray-box model, 264
- gross-defects, 435
- ground loop, 260
- growth fault, 61, 65
- Grumberg, 625
- guard pin, 592
- guard wire, 592
- guardbanding, 21
- Gulati, 444, 448, 449, 626
- Gupta, 621

- Hachtel, 625
- half-channel test, 366, 369
- Hamida, 398, 402
- Hamiltonian sequence, 287
- Hamming distance, 252, 600, 617
- hard core, 606
- hard fault, 387
- hard-core, 465, 498
- hardware description language, 91, 569
- hardware diffractor, 512
- hardware partitioning, 501
- hardware sharing, 150
- hardware test, 59
- hardware-software co-design, 597
- Harjani, 385
- harmonic analog test, 398
- harmonic distortion test, 374
- Hawkins, 626
- Hayes, 287, 514, 625
- hazard, 540
- hazard elimination, 169
- hazard-free stuck-fault test, 69
- HDL, 91
- headline, 193
- headline objective, 194
- Healy, 622
- Henftling, 203
- heterodyning, 315, 352
- heuristic, 176
- heuristic algorithm, 176
- hierarchical decomposition, 491
- hierarchical sensitivity analysis, 399
- hierarchical test, 525
- hierarchical test generation, 206
- high impedance state, 98
- high level, 60
- high-speed operation test, 298
- high-speed reload server, 26
- high-speed undersampling, 341
- HIGHZ instruction, 563, 585, 587
- HILO, 109
- HITEC, 221, 224
- Hnatek, 623
- hold time test, 33
- Holland, 246
- Holzman, 625
- homotopy/simulation continuation, 393
- Hopfield model, 165
- Householder, 393–396
- Householder's formula, 395
- Hsiao, M. S., 247
- Hsiao, M. Y., 625
- Huang, 626
- humidity, 260
- hybrid cellular automaton, 511
- hybrid pattern generator, 540, 543
- hyperactive fault, 62
- hypergeometric probability function, 122
- hysteresis, 326

- IBM TestBench, 248
- ICT, 491, 605
- IDCODE instruction, 562, 585
- ideal converter transfer function, 322
- ideal white noise measurement, 381
- idempotent coupling fault, 258, 270
- idle channel noise, 374
- IEEE 1149.1 standard, 549
- IEEE 1149.4 standard, 575
- IEEE 1450 standard, 607
- IEEE P1500 standard, 607
- IFA, 294
- IFA-13 and Delay test, 296
- IFA-13 test, 295, 296
- IFA-6 test, 295
- IFA-9 and Delay test, 296
- IFA-9 test, 295
- ILE, 326
- IM, 315, 323, 349, 356
- image number, 353
- immediate assignment of unique signals, 193
- impedance matching, 578
- implication arc, 202
- implication graph, 165, 201
- implication graph AND node, 203
- implication procedure, 178
- implication stack, 173
- implicit clock model, 231
- implicit clock rate, 340
- implicit digitization, 377
- improved unique sensitization procedure, 198
- in pin, 571
- in situ testing, 501
- in-band test, 363
- in-circuit test, 21, 491, 549, 575, 605
- in-phase component, 344
- incoming inspection, 17
- incoming inspection test, 20
- incompatible cubes, 177
- incorrect component orientation, 575
- increasing returns to scale, 41
- incremental sensitivity, 398
- independent analog parameter, 404
- independent faults, 206
- indistinguishability condition, 73
- inductance, 12
- inductive fault analysis, 258, 264, 294
- inertial delay, 99
- infant mortality failures, 20